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thin solid films

Contents

Letters

On the properties of $Cu_XC_{1-X}Te$: a novel semiconductor alloy
S. Jiménez-Sandoval, S. López-López, B.S. Chao, M. Meléndez-Lira 1

Probing the surface forces of atomic layered $SrTiO_3$ films by atomic force microscopy
H. Tanaka, H. Tabata, T. Kawai 4

Yellow organic electroluminescent device based on novel thiophene Al complex as an emitting layer
K. Okada, Y.-F. Wang, T. Nakaya 8

Structural and magnetoresistive properties of sputtered co/cu multilayers in the vicinity of the first maximum of magnetoresistance
E. Rozenberg, D. Mogilaynski, J. Pelleg, G. Gorodesky, R. Somekh 11

Synthesis and Characterization

Characteristics and sensing properties of dipped $La_{0.8}Sr_{0.2}Co_{1-x}Ni_xO_{3-\delta}$ film for CO gas sensors
C.M. Chiu, Y.H. Chang 15

Effects of octa decyl thiol (ODT) treatment on the gallium arsenide surface and interface state density
K. Remashan, K.N. Bhat 20

Growth behavior and surface morphology of Ag rough thin films deposited on silicone oil surfaces
C.-M. Fenga, H.-L. Gea, M.-R. Tang, G.-X. Yea, Z.-K. Jiaoa 30

Electrostatic sol-spray deposition (ESSD) and characterisation of nanostructured TiO_2 thin films
C.H. Chen, E.M. Kelder, J. Schoonman 35

Phase diagrams for CVD diamond deposition from halogen-containing gas phase
Z.-J. Liu, D.W. Zhang, J.-Y. Zhang, Y.-Z. Wan, J.-T. Wang 42

Characterization of boron-doped tin oxide thin films
S.A. Nasser 47

Mechanical and chemical properties of organic coatings applied to metallic sheet substrates
A.A. Roche, J. Guillemenet 52

Pulsed laser deposition of conducting porous La-Sr-Co-O films
X. Chen, N.J. Wu, D.L. Ritums, A. Ignatiev 61

The effects of ion irradiation on NiTi shape memory alloy thin films
F. Goldberg, É.J. Knystautas 67

Influence of oxygen and nitrogen on the growth of hot-filament chemical vapor deposited diamond films
Z. Yu, U. Karlsson, A. Flodström 74

Mechanical, optical and structural properties of TiO_2 and MgF_2 thin films deposited by plasma ion assisted deposition
G. Atanassov, J. Turlo, J K. Fu, Y.S. Dai 83

Evidence of ω-phase in ion beam sputtered zirconium thin films
L. Pichon, T. Girardeau, F. Lignou, A. Straboni 93

Tungsten-containing amorphous carbon films deposited by pulsed vacuum arc
O.R. Monteiro, M.-P. Delplancke-Ogletree, I.G. Brown 100

Growth of spinel zinc thioindionate thin film by single-source MOCVD
R. Nomura, H. Matsuda, T. Miyai, A. Baba 108

Effects of organic As-precursors on the incorporation of In and Ga into (GaIn)As films grown by metal-organic vapor-phase epitaxy
G. Kirpal, M. Gerhardt, V. Gottschalch, R. Franzheld, H.C. Semmelhack 113

Films obtained by plasma polymerization of pyrrole
G.J. Cruz, J. Morales, R. Olayo 119

Structural investigations on ultrathin Mo layers in a-Si:H with emphasis on the island–continuous layer transition
M. Löhmann, F. Klabunde, J. Bläsing, P. Veit, T. Drüsedau 127

Electrical and gated photoluminescence intensity studies on Schottky and oxidized Schottky structures
A. Ahaitouf, A. Bath 136

In situ photoluminescence characterization of porous silicon formation
N. Chi, D.L. Phillips, K.-Y. Chan 142

Photoelectrochemical studies of dye-sensitizedpolycrystalline titanium oxide thin films prepared by sputtering
M. Gómez, J. Rodriguez, S.-E. Lindquist, C.G. Granqvist 148

Simple method for the determination of optical parameters of inhomogeneous thin films
L. De Caro, M.C. Ferrara 153

Characterization of SnO_2 thin films through thermoelectric power measurements
G. Gordillo, B. Paez, C. Jácome, J.M. Flórez 160

Free-carrier plasma resonance effects and electron transport in reactively sputtered degenerate ZnO:Al films
S. Brehme, F. Fenske, W. Fuhs, E. Nebauer, M. Poschenrieder, B. Selle, I. Sieber 167

An X-ray diffraction study of interface roughness and diffusion in Ag/Pd superlattices
K. Temst, M.J. Van Bael, C. Van Haesendonck, Y. Bruynseraede, D.G. de Groot, N. Koeman, R. Griessen 174

Surfaces, Interfaces and Colloidal Behaviour

Electroepitaxy: the control of the kinetics and morphology of InSb
L.A. Borisova, Z.L. Akkerman, T.P. Koretskaya 180

Enhancement of TiC/stainless steel interfaces by N^--implantation
T.W. Kang, C.Y. Hong, C.K. Chung, T.W. Kim 184

Metallurgical, Protective and Hard Layers

Hardness enhancement of sputtered Ni_3Al/Ni multilayers
S. Tixier, P. Böni, H. Van Swygenhoven 188

Tribological performance and tribochemistry of nanocrystalline WC/amorphous diamond-like carbon composites
A.A. Voevodin, J.P. O'Neill, J.S. Zabinski 194

Elastic modulus of plasma-sprayed coatings determined by indentation and bend tests
H.-J. Kim, Y.-G. Kweon 201

Mechanics and Nanomechanics of Thin Layers

Adhesion and failure mechanisms of tungsten–carbon containing multilayer and graded coatings subjected to scratch tests
E. Harry, A. Rouzaud, P. Juliet, Y. Pauleau 207

Thin film TiC/TaC thermocouples
H.D. Bhatt, R. Vedula, S.B. Desu, G.C. Fralick 214

Electronics, Optics and Opto-electronics

Chemical vapor etching of copper using oxygen and 1,1,1,5,5,5-hexafluoro-2,4-pentanedione
R. Steger, R. Masel 221

Ellipsometric studies of porous silicon
V.A. Makara, V.A. Odarych, O.V. Vakulenko, O.I. Dacenko 230

The surface reaction and diffusion of NO_2 in lead phthalocyanine thin film
C. Hsieh, C.J. Liu, Y.H. Ju 238

Scanning photothermal beam deflection- and scanning photothermal displacement-imaging of polymer channel waveguides: a comparison
M.J.S Kreiter, S. Mittler-Neher 244

Enhanced-Raman scattering from organic thin films in an attenuated total reflection geometry mediated by half-leaky guided modes
S. Hayashi, T. Kitagawa, Y. Sekiguchi, T. Kume 249

Analytical design of antireflection coatings for silicon photovoltaic devices
P. Nubile 257

Study of single and double Si δ-doped GaAs layers by spectral photoconductivity measurements
J. Oswald, J. Pastrňák, F. Karel, O. Petříček, A. Salokatve 262

Langmuir–Blodgett, Biological and Related Films

Copper-oxide thin films prepared from Langmuir–Blodgett films
M. Schurr, M. Seidl, A. Brugge, H. Voit 266

Study of mixed system in monolayers and multilayers transferred by Langmuir–Blodgett technique
V.R. Shembekar, A. Dhanabalan, S.S. Talwar, A.Q. Contractor 270

Monolayers and Langmuir–Blodgett films of a palladium(ii)-tetraazaporphyrin
R. Ricceri, G. Ricciardi, F. Lelj, G. Martini, G. Gabrielli 277

Thin Film Devices, Sensors and Actuators

Aluminium oxide tunnel junctions: influence of preparation technique, sample geometry and oxide thickness
D. Diesing, A.W. Hassel, M.M. Lohrengel 282

Condensed Matter Film Behaviour

Structure and microtribological behavior of Teflon and Teflon/Si_3N_4 micro-assembling film
J. Wang, X. Lu, S. Wen, H. Li, L. Wang 291

Morphology changes of thin Pd films grown on SiO_2: influence of adsorbates and temperature
M. Eriksson, L. Olsson, U. Helmersson, R. Erlandsson, L.-G. Ekedahl 297

Low-energy electron diffraction, Scanning tunneling microscopy, and X-ray photoemission spectroscopy investigations of DMe-DCNQI on Cu(110)
H. Kopf, C. Seidel, H. Fuchs 307

Photoconductivity of Si/Ge Buffers, superlattices, and multiple quantum wells
D. Menzel, W. Koschinski, K. Dettmer, J. Schoenes 312

Corrigendums

Corrigendum to "New γ-In_2Se_3/TCO (SnO_2 or ZnO) thin films rectifying heterojunction"
S. Marsillac J.C. Bernède 317

Erratums

Erratum to "Valence band splitting in $Cd_{(1-x)}Zn_xTe$ epilayers"
K. Cohen, R. Beserman, S. Stolyarova, R. Weil, Y. Nemirovsky 318

Author Index 319

Subject Index 321

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